TATES PATENT AND TRADEM IN THE UNIT

10/23/03 Moun

In re Application of

Bojarczuk, et al.

Serial No.:

09/755,16 (La mai

Group Art Unit:

2826

Filed:

January 8, 2001

Examiner:

Quinto, Kevin V.

For:

ALUMINUM NITRIDE AND ALUMINUM OXIDE/ALUMINUM NITRIDE HETEROSTRUCTURE GATE DIELECTRIC STACK BASED FIELD EFFECT

TRANSISTORS AND METHOD FOR FORMING SAME

Commissioner for Patents Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to Applicants' duty of disclosure under 37 CFR §1.56, Applicants respectfully bring the following documents to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the Applicants are aware.

The Commissioner is hereby authorized to charge the Information Disclosure Statement fee of \$180.00 to Assignee's Deposit Account No. 50-0510.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0510.

Respectfully submitted,

Registration No. 39,715

McGinn & Gibb, PLLC

Intellectual Property Law 8321 Old Courthouse Road, Suite 200

Vienna, VA 22182-3817

(703) 761-4100

Customer No. 21254

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

Docket Number (Optional)	Application Number 09/755,164				
YOR920000642					
Applicant(s) Bojarczuk, et al.					
Filing Date	Group Art Unit				
January 8, 2001	2826				

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	,	•		U.S. PAT	ENT DOCUMENTS				
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	1	IG DATE
		4,097,314	09/27/1978	Schlesie	er, et al.			11 (3.2	Urmail
		5,929,467	07/27/1999	Kawai,	et al.				
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XAMINER	l: Initia	il if citation considered, whether	or not citation is in	conformanc	e with MPEP Section 609	9; Draw line throug	h citation if not	in conform	ance and

F rm PTO-A820 (also form PTO-1449)

not considered. Include copy of this form with next communication to applicant.